

Application of p-i-n photodiodes to charged particle fluence measurements beyond 10^{15} 1-MeV-neutron-equivalent/cm²

Wednesday 6 June 2018 11:30 (20 minutes)

Methods are developed for the application of forward biased p-i-n photodiodes to measurements of charged particle fluence beyond 10^{15} 1-MeV-neutron-equivalent/cm². An order of magnitude extension of the regime where forward voltage can be used to infer fluence is achieved for OSRAM BPW34F devices.

Primary authors: GRUMMER, Aidan (University of New Mexico (US)); SEIDEL, Sally (University of New Mexico (US)); HOEFERKAMP, Martin (University of New Mexico (US)); RAJEN, Ivan Vikram (University of New Mexico (US))

Presenter: GRUMMER, Aidan (University of New Mexico (US))

Session Classification: Defect and Material Characterization